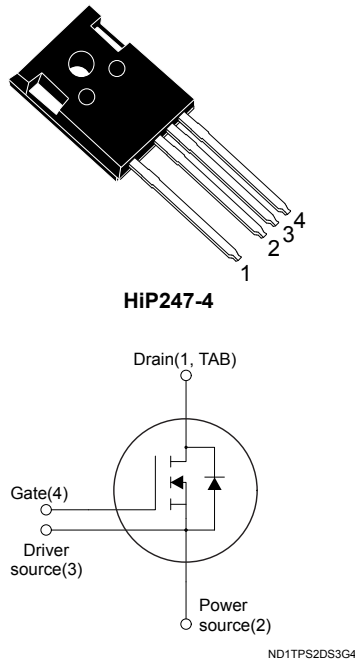


Automotive-grade silicon carbide Power MOSFET 1200 V, 75 mΩ typ., 33 A in an HiP247-4 package



Features

Order code	V_{DS}	$R_{DS(on)}$ max.	I_D
SCTWA40N12G24AG	1200 V	105 mΩ	33 A

- AEC-Q101 qualified 
- Very fast and robust intrinsic body diode
- Extremely low gate charge and input capacitance
- Very high operating junction temperature capability ($T_J = 200\text{ }^{\circ}\text{C}$)
- Source sensing pin for increased efficiency

Applications

- Main inverter (electric traction)
- DC/DC converter for EV/HEV
- On board charger (OBC)

Description

This silicon carbide Power MOSFET device has been developed using ST's advanced and innovative 2nd generation SiC MOSFET technology. The device features remarkably low on-resistance per unit area and very good switching performance. The variation of switching loss is almost independent of junction temperature.

Product status link

[SCTWA40N12G24AG](#)

Product summary

Order code	SCTWA40N12G24AG
Marking	SCT40N12G24AG
Package	HiP247-4
Packing	Tube

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	1200	V
V_{GS}	Gate-source voltage	-10 to 22	V
	Gate-source voltage (recommended operating values)	-5 to 18	
	Gate-source voltage (pulsed, $t_p = 25$ ns repetitive overshoot during switching for an accumulated time of 10 h)	-11 to 25	
I_D	Drain current (continuous) at $T_C = 25$ °C	33	A
	Drain current (continuous) at $T_C = 100$ °C	25	
$I_{DM}^{(1)}$	Drain current (pulsed)	100	A
P_{TOT}	Total power dissipation at $T_C = 25$ °C	290	W
T_{stg}	Storage temperature range	-55 to 200	°C
T_J	Operating junction temperature range		°C

1. Pulse width limited by safe operating area.

Table 2. Thermal data

Symbol	Parameter	Value	Unit
R_{thJC}	Thermal resistance, junction-to-case	0.6	°C/W
R_{thJA}	Thermal resistance, junction-to-ambient	40	°C/W

2 Electrical characteristics

$T_C = 25\text{ }^{\circ}\text{C}$ unless otherwise specified.

Table 3. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0\text{ V}$, $I_D = 1\text{ mA}$	1200			V
I_{DSS}	Zero gate voltage drain current	$V_{DS} = 1200\text{ V}$, $V_{GS} = 0\text{ V}$			10	μA
I_{GSS}	Gate-body leakage current	$V_{DS} = 0\text{ V}$, $V_{GS} = -10\text{ to }22\text{ V}$			± 100	nA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 1\text{ mA}$	1.9	3.2	5.0	V
$R_{DS(on)}$	Static drain-source on-resistance	$V_{GS} = 18\text{ V}$, $I_D = 20\text{ A}$		75	105	m Ω
		$V_{GS} = 18\text{ V}$, $I_D = 20\text{ A}$, $T_J = 200\text{ }^{\circ}\text{C}$		195		

Table 4. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{DS} = 800\text{ V}$, $f = 1\text{ MHz}$, $V_{GS} = 0\text{ V}$	-	1230	-	pF
C_{oss}	Output capacitance		-	56	-	pF
C_{rss}	Reverse transfer capacitance		-	15	-	pF
Q_g	Total gate charge	$V_{DS} = 800\text{ V}$, $V_{GS} = -5\text{ to }18\text{ V}$, $I_D = 20\text{ A}$	-	63	-	nC
Q_{gs}	Gate-source charge		-	15	-	nC
Q_{gd}	Gate-drain charge		-	20	-	nC
R_G	Gate input resistance	$f = 1\text{ MHz}$, $I_D = 0\text{ A}$	-	1	-	Ω

Table 5. Switching energy

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
E_{on}	Turn-on switching energy	$V_{DD} = 800\text{ V}$, $I_D = 20\text{ A}$, $R_G = 4.7\text{ }\Omega$, $V_{GS} = -5\text{ to }18\text{ V}$	-	235	-	μJ
E_{off}	Turn-off switching energy		-	77	-	μJ

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 800\text{ V}$, $I_D = 20\text{ A}$, $R_G = 4.7\text{ }\Omega$, $V_{GS} = -5\text{ to }18\text{ V}$	-	11	-	ns
t_r	Rise time		-	5	-	ns
$t_{d(off)}$	Turn-off-delay time		-	18	-	ns
t_f	Fall time		-	13	-	ns

Table 7. Reverse SiC diode characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
V_{SD}	Diode forward voltage	$I_{SD} = 20\text{ A}$, $V_{GS} = 0\text{ V}$	-	3.4	-	V
t_{rr}	Reverse recovery time	$I_{SD} = 20\text{ A}$, $di/dt = 2000\text{ A}/\mu\text{s}$, $V_{DD} = 800\text{ V}$, $V_{GS} = -5\text{ to }18\text{ V}$	-	10	-	ns
Q_{rr}	Reverse recovery charge		-	132	-	nC
I_{RRM}	Reverse recovery current		-	20	-	A

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

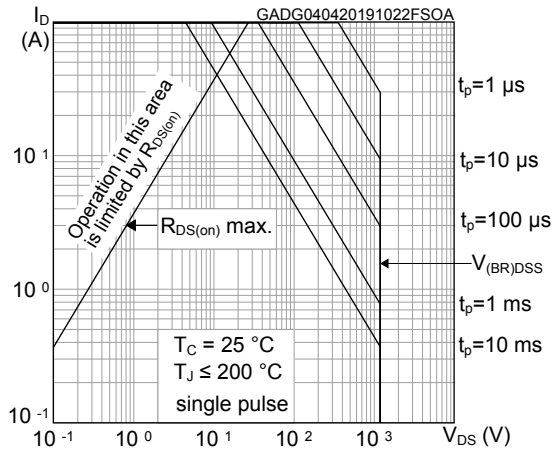


Figure 2. Maximum transient thermal impedance

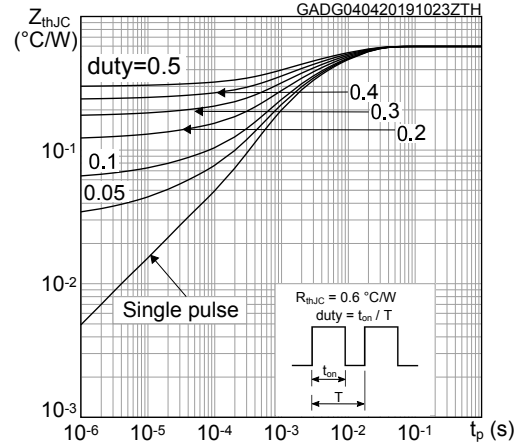


Figure 3. Output characteristics ($T_J = -50\text{ °C}$)

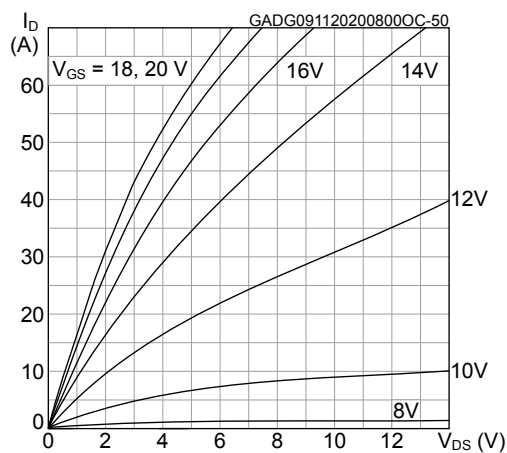


Figure 4. Output characteristics ($T_J = 25\text{ °C}$)

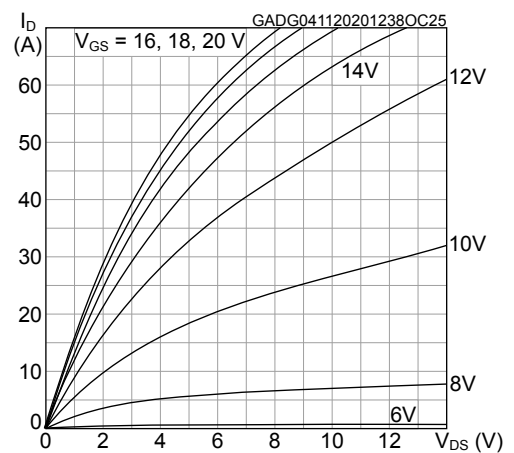


Figure 5. Output characteristics ($T_J = 200\text{ °C}$)

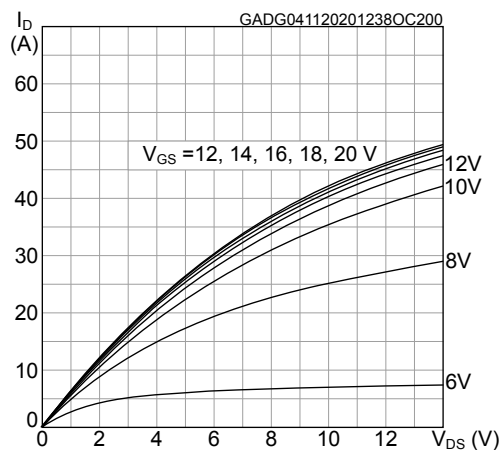


Figure 6. Transfer characteristics

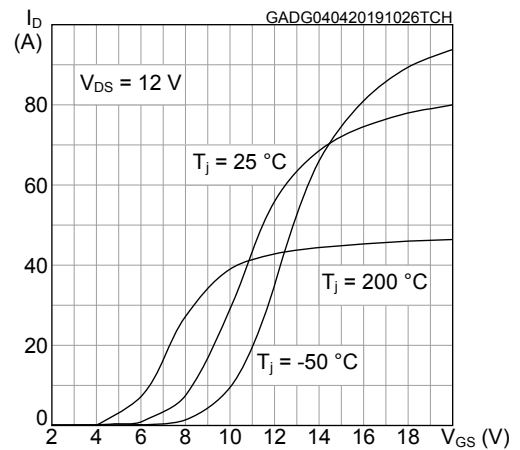


Figure 7. Total power dissipation

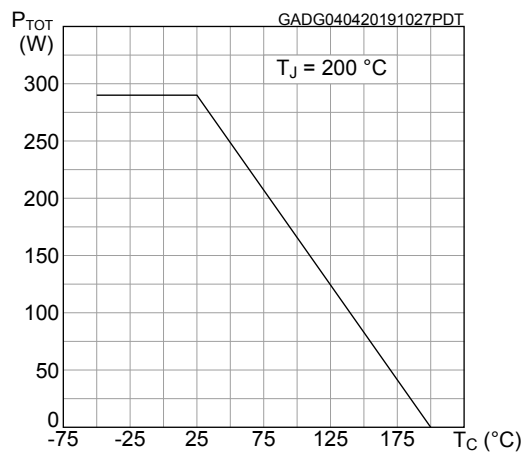


Figure 8. Gate charge vs gate-source voltage

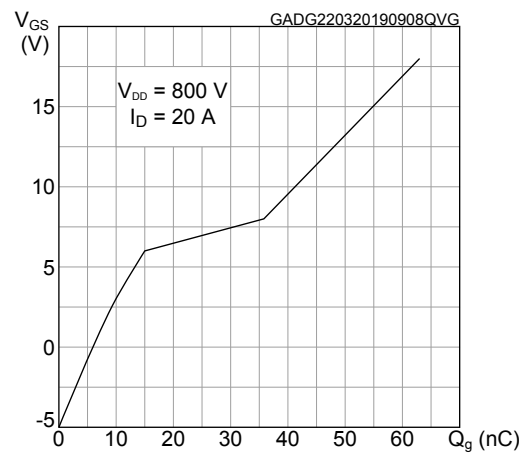


Figure 9. Capacitance variations

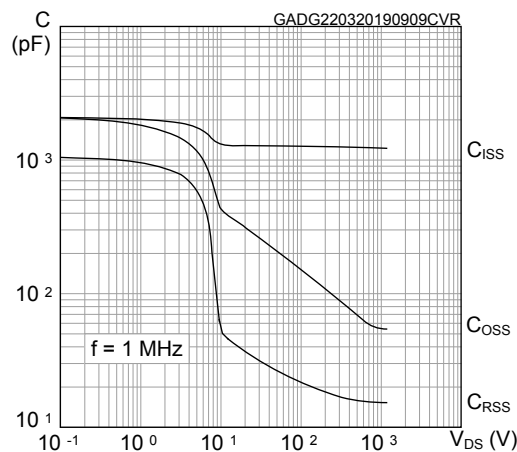


Figure 10. Switching energy vs drain current

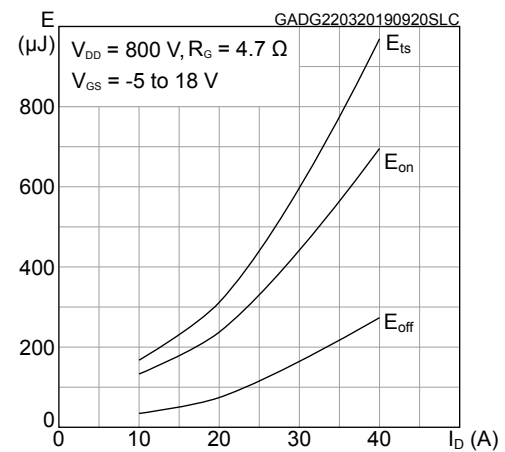


Figure 11. Switching energy vs junction temperature

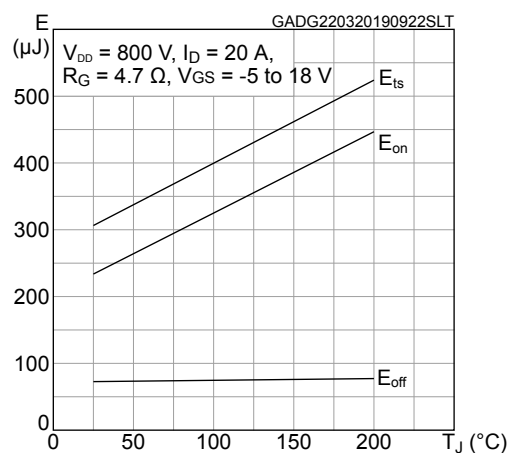


Figure 12. Normalized $V_{(BR)DSS}$ vs temperature

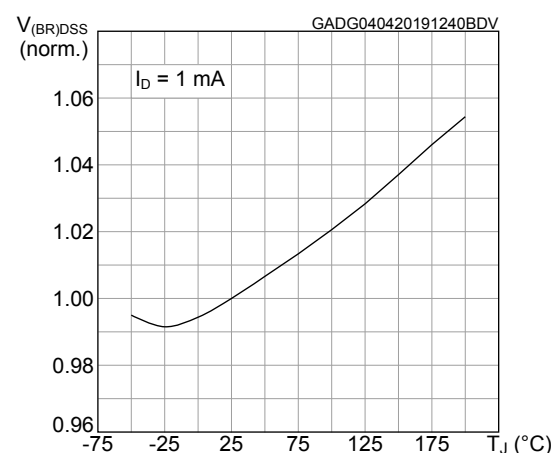


Figure 13. Normalized on-resistance vs temperature

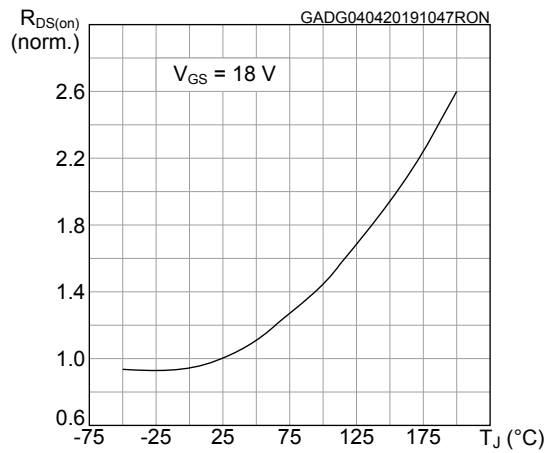


Figure 14. Normalized gate threshold voltage vs temperature

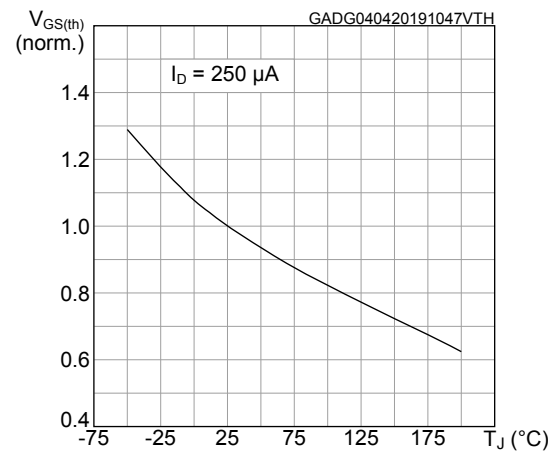


Figure 15. Reverse conduction characteristics ($T_J = -50\text{ }^\circ\text{C}$)

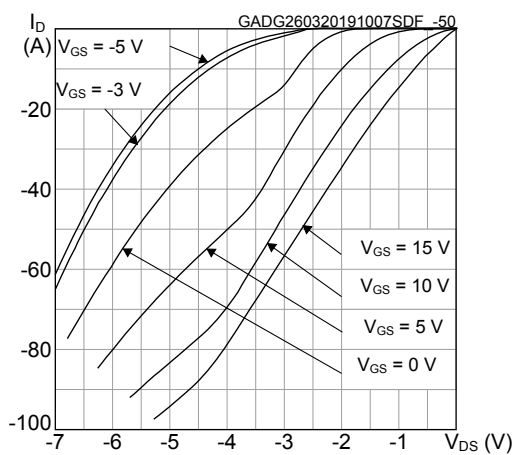


Figure 16. Reverse conduction characteristics ($T_J = 25\text{ }^\circ\text{C}$)

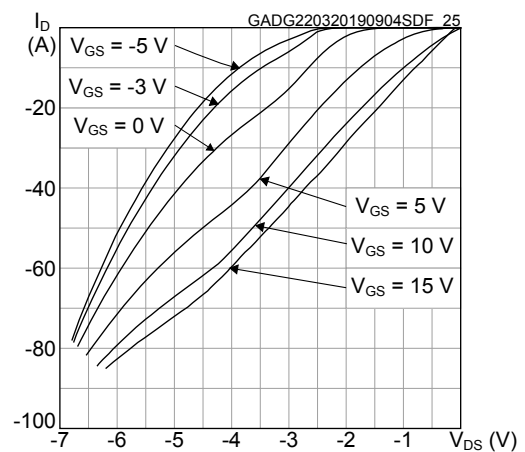
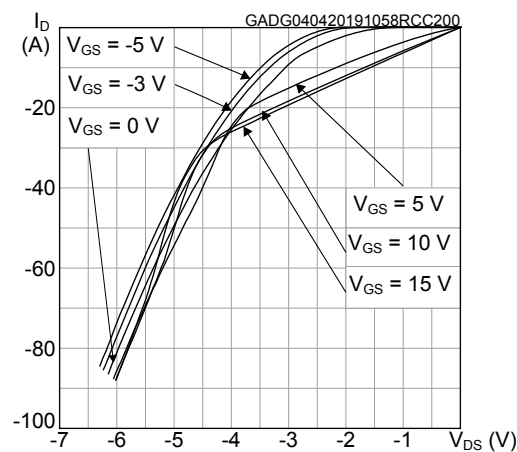


Figure 17. Reverse conduction characteristics ($T_J = 200\text{ }^\circ\text{C}$)

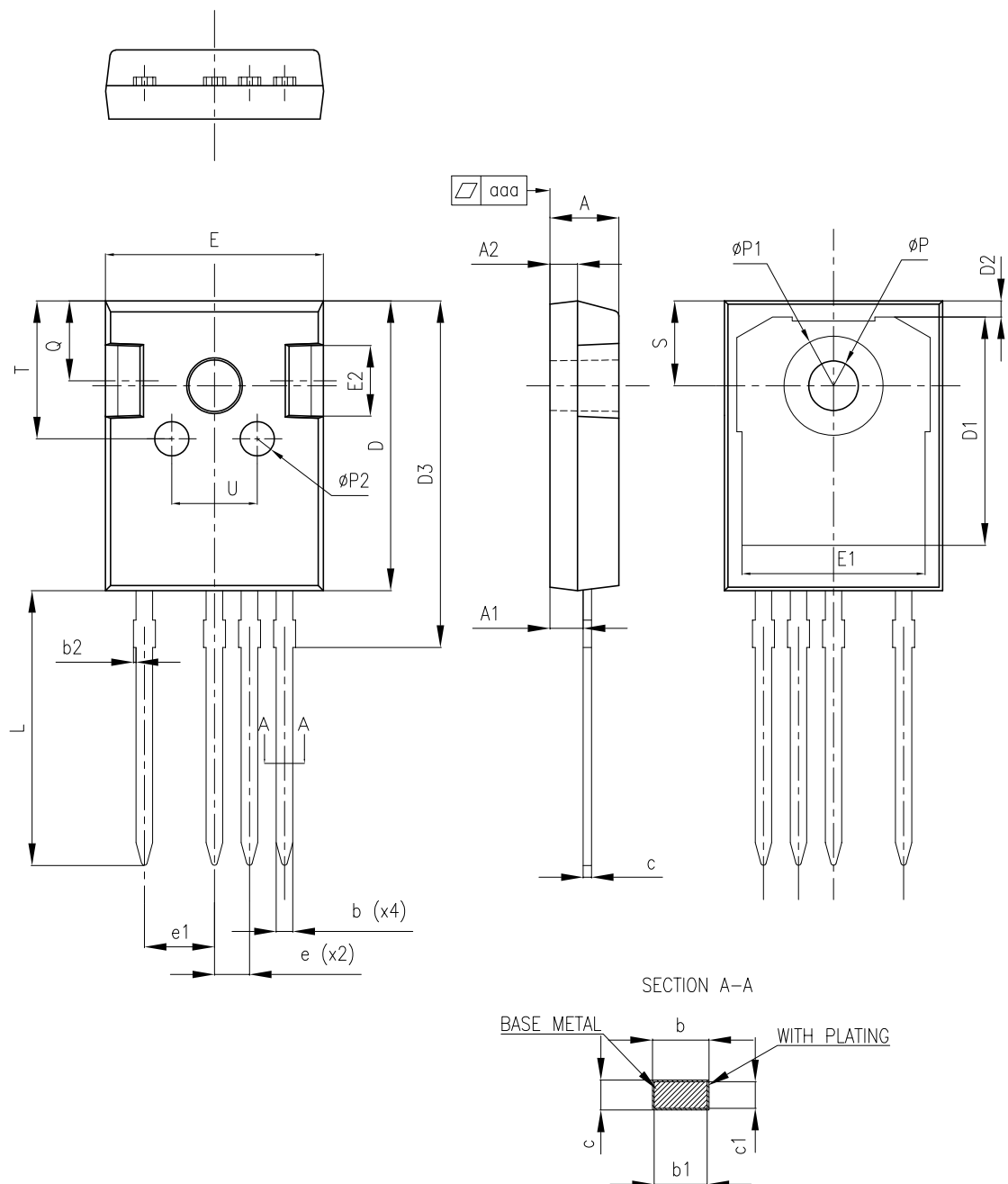


3 Package information

In order to meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

3.1 HiP247-4 package information

Figure 18. HiP247-4 package outline



8405626_Rev_3

Table 8. HiP247-4 mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.90	5.00	5.10
A1	2.31	2.41	2.51
A2	1.90	2.00	2.10
b	1.16		1.29
b1	1.15	1.20	1.25
b2	0		0.20
c	0.59		0.66
c1	0.58	0.60	0.62
D	20.90	21.00	21.10
D1	16.25	16.55	16.85
D2	1.05	1.20	1.35
D3	24.97	25.12	25.27
E	15.70	15.80	15.90
E1	13.10	13.30	13.50
E2	4.90	5.00	5.10
E3	2.40	2.50	2.60
e	2.44	2.54	2.64
e1	4.98	5.08	5.18
L	19.80	19.92	20.10
P	3.50	3.60	3.70
P1			7.40
P2	2.40	2.50	2.60
Q	5.60		6.00
S		6.15	
T	9.80		10.20
U	6.00		6.40
aaa		0.04	0.10

Revision history

Table 9. Document revision history

Date	Revision	Changes
24-Nov-2020	1	First release.
24-Jun-2021	2	Updated <i>Table 6. Switching times.</i>
27-Sep-2021	3	Modified <i>Table 1. Absolute maximum ratings.</i>
22-Nov-2021	4	Modified <i>Figure 1. Safe operating area</i> and <i>Figure 2. Maximum transient thermal impedance.</i>
20-Oct-2023	5	Updated <i>Table 7. Reverse SiC diode characteristics.</i>



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